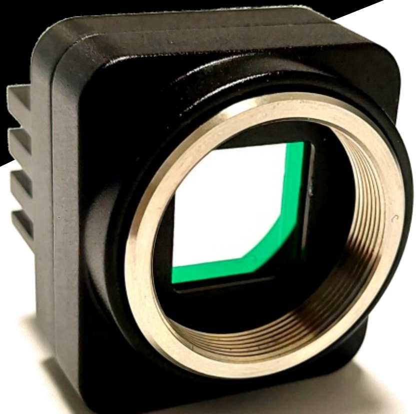
TAKUME Camera

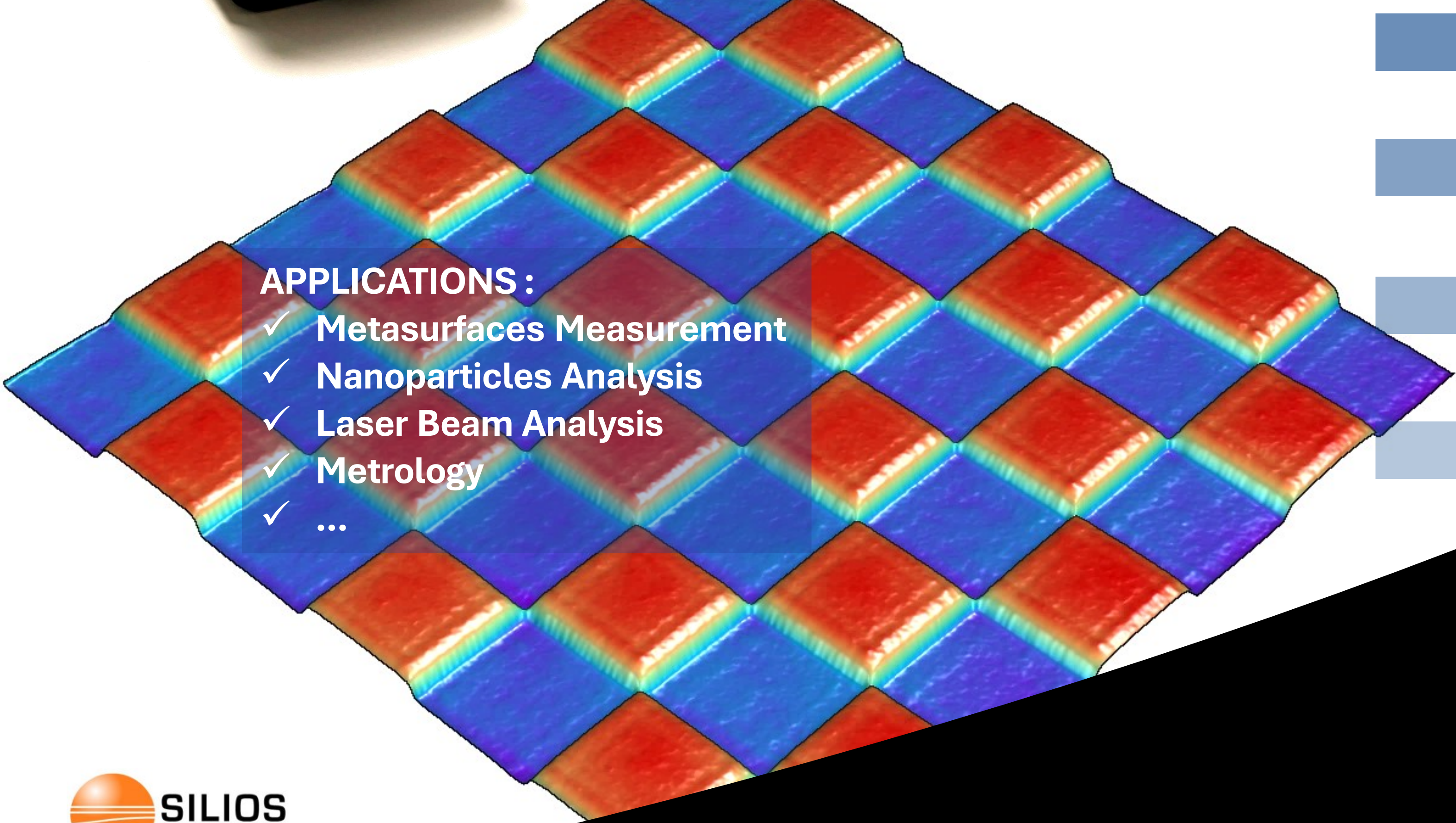
SWIR Wavefront Sensing

SILIOS Technologies' TAKUME Cameras are based on the *COLOR-SHADES®* technology (hybridization of micro-optical chips onto image sensors).

The TAKUME Snapshot SWIR Wavefront Cameras capture 1.3Mpx raw images to provide 432x344 pixels wavefront images.



Snapshot Camera
Wavefront Image
900-1700 nm Spectral Range
1296 x 1032 Native Resolution
432 x 344 Wavefront Resolution
12 Bits
USB3.0
External Trigger Input



APPLICATIONS :

- ✓ **Metasurfaces Measurement**
- ✓ **Nanoparticles Analysis**
- ✓ **Laser Beam Analysis**
- ✓ **Metrology**
- ✓ **...**

SILIOS Technologies
ZI Peynier-Rousset
Rue Gaston Imbert prolongée
13790 Peynier (France)

Tel : +33 (0)4 42 53 89 60
Fax : +33 (0)4 42 53 89 59
Email : contact@silios.fr
www.silios.com

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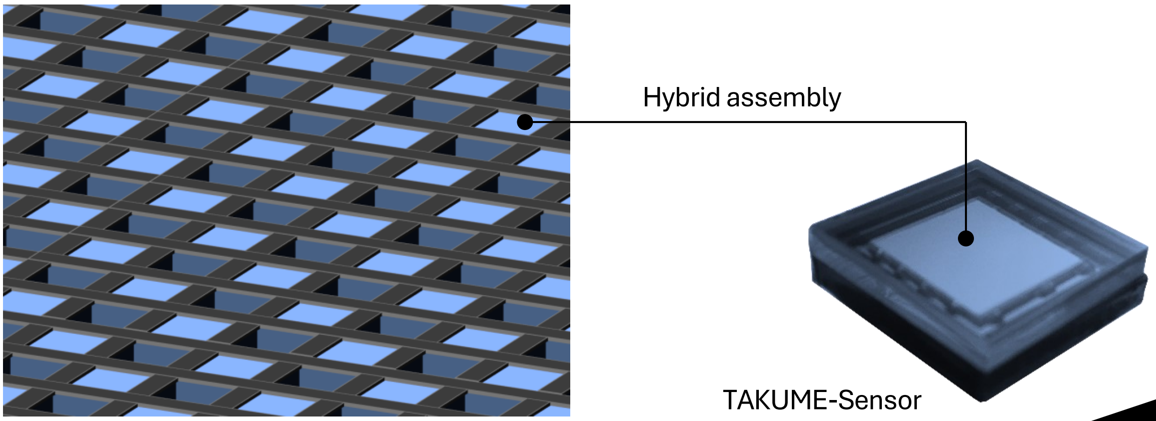
SWIR Wavefront Sensing

FEATURES	
General	
Wavelength Range	900-1700 nm
InGaAs Sensor	
InGaAs Sensor Native Resolution	1296 x 1032 (1.3MP)
InGaAs Sensor Pixel Pitch	5.0 µm
InGaAs Sensor Area	6.48 x 5.16 mm^2
Wavefront Image	
Wavefront Image Definition	432 x 344 (*)
Spatial Resolution	15.0 µm (**)
Sensitivity	< 1 nm RMS
Wavefront Camera	
Camera Max Frame Rate	68 fps
Wavefront Live Frame Rate	~20-30 fps (***)
Bit Depth	12 bits
Digital Output/Power Supply	USB3.0
External Trigger Input	Yes
Lens Mount	C-type or CS-type
Dimensions	34 x 38 x 35 mm^3
Weight	70 g

(*) possible 1296x1032 resolution for viewing

(**) spatial resolution at sample level with a x40 magnification: 375 nm

(***) depends on the PC configuration



Pixelated Diffractive Filter

TAKUME-Sensor

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